



8th XFEL 5-way collaboration meeting

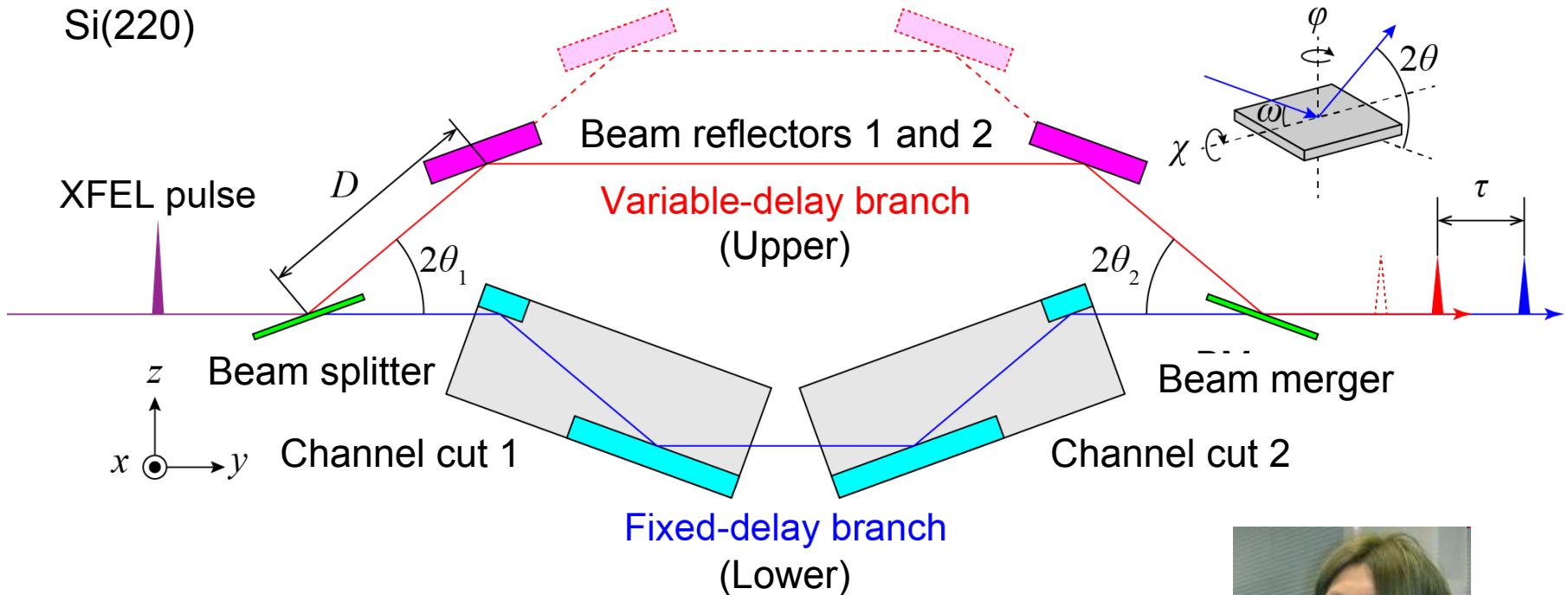
X-ray optics development at SACLA

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Contents

1. Split-delay optics
2. HBT experiment
3. Self seeding with micro channel-cut crystals

Crystal arrangement of SDO system @SACLA



Crystal diffraction:

Large time delays (~ sub-ns) with fs resolution
High energy resolutions ($\Delta E/E < 1 \times 10^{-4}$)



Osaka-san
(Osaka U → SACLA)

Two independent delay branches:

Enables access to time zero

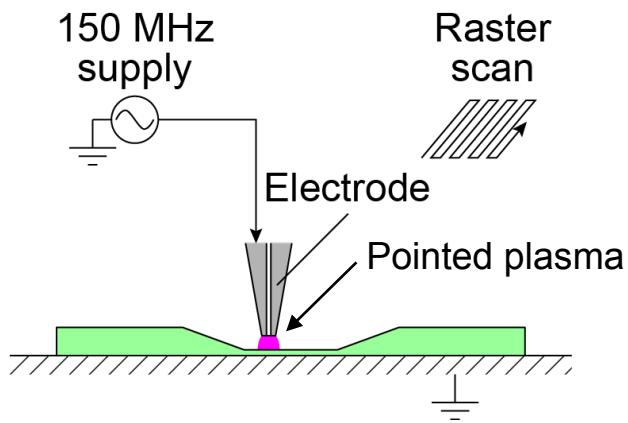
Collaboration with
SLAC & DESY

Use of channel cuts:

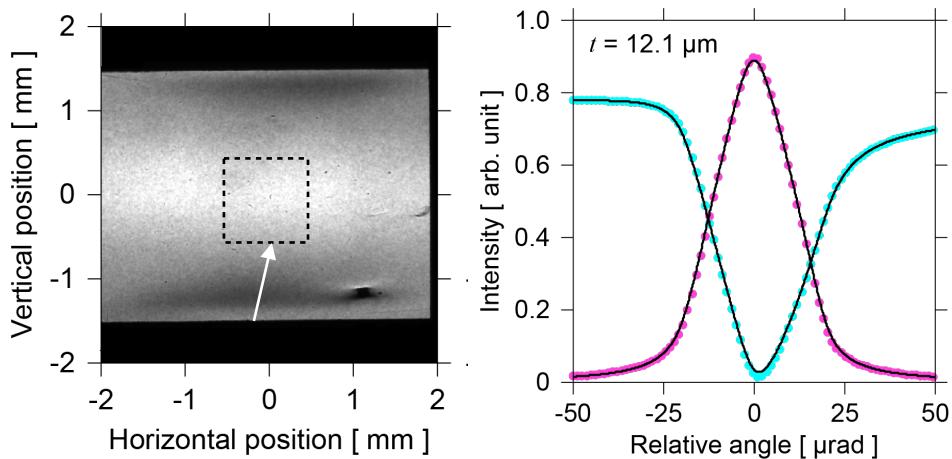
Much stabilized operation

Key optical devices

Thin crystal beam splitter/merger:

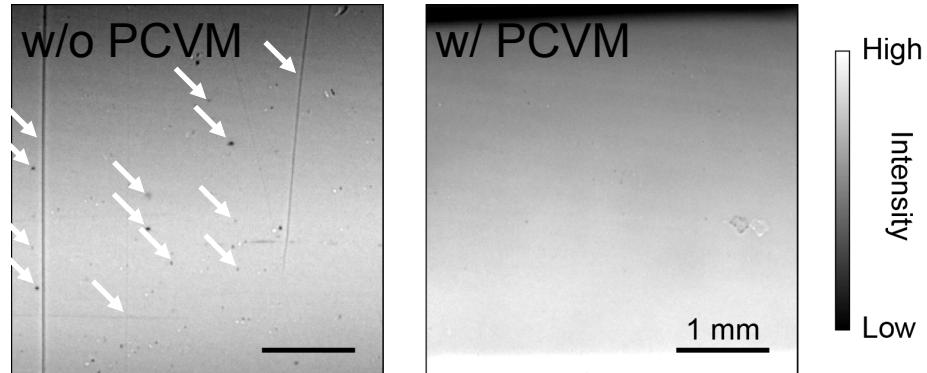
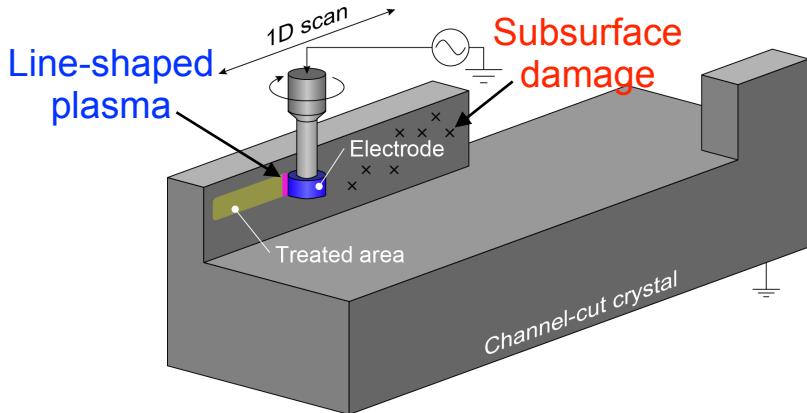


T. Osaka et al., OE 21, 2823 (2013).



Channel cut crystals:

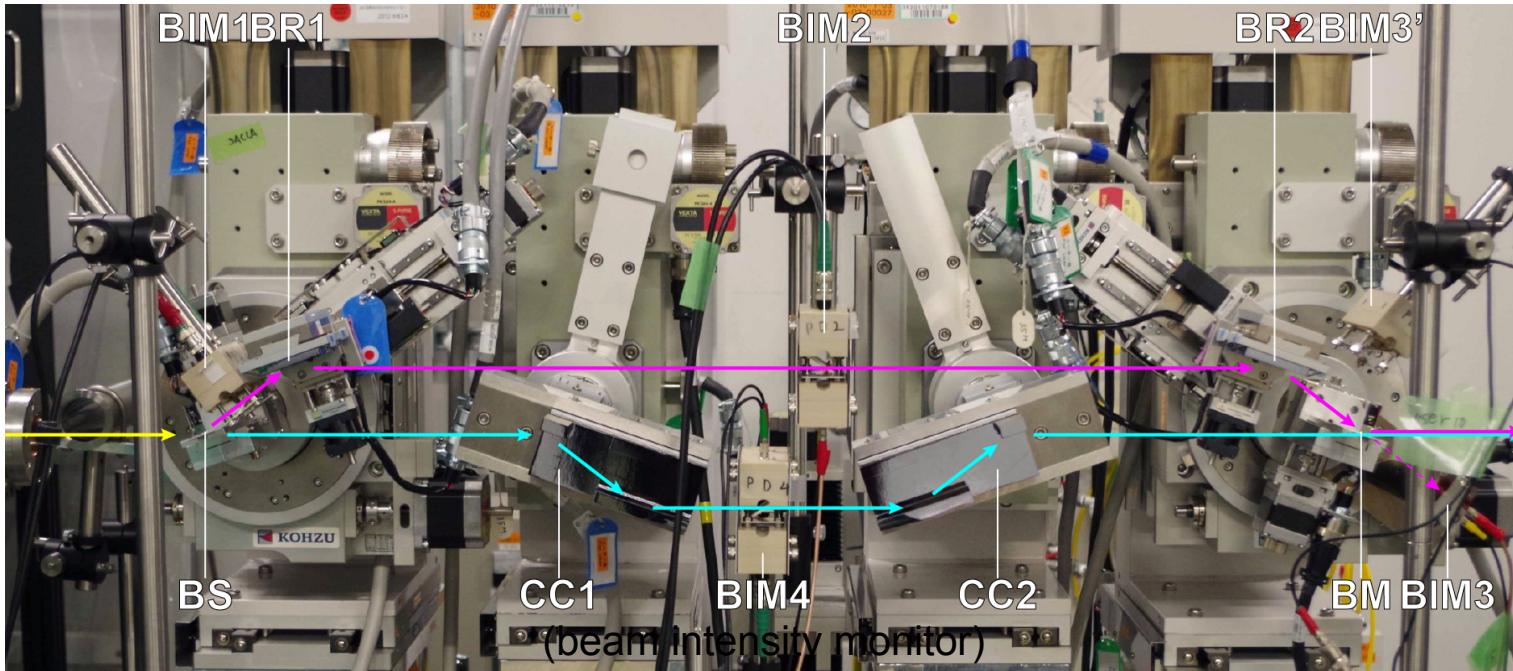
T. Hirano, T. Osaka et al., in reviewed.



Both crystal devices were fabricated using a plasma etching technique.

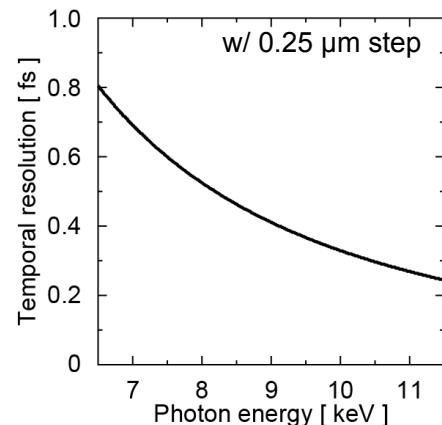
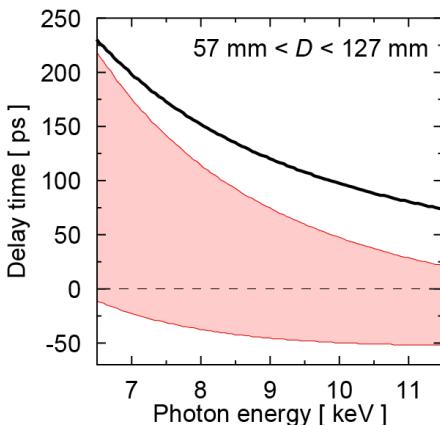
PCVM: non-physical contact, damage-free, controllable plasma size

Prototype SDO



Built with all commercial components for motion control.

Each intensity diagnostic module consists of thin Kapton film scatter and photodiode.



Photon energy range
6.5 keV ~ 11.5 keV

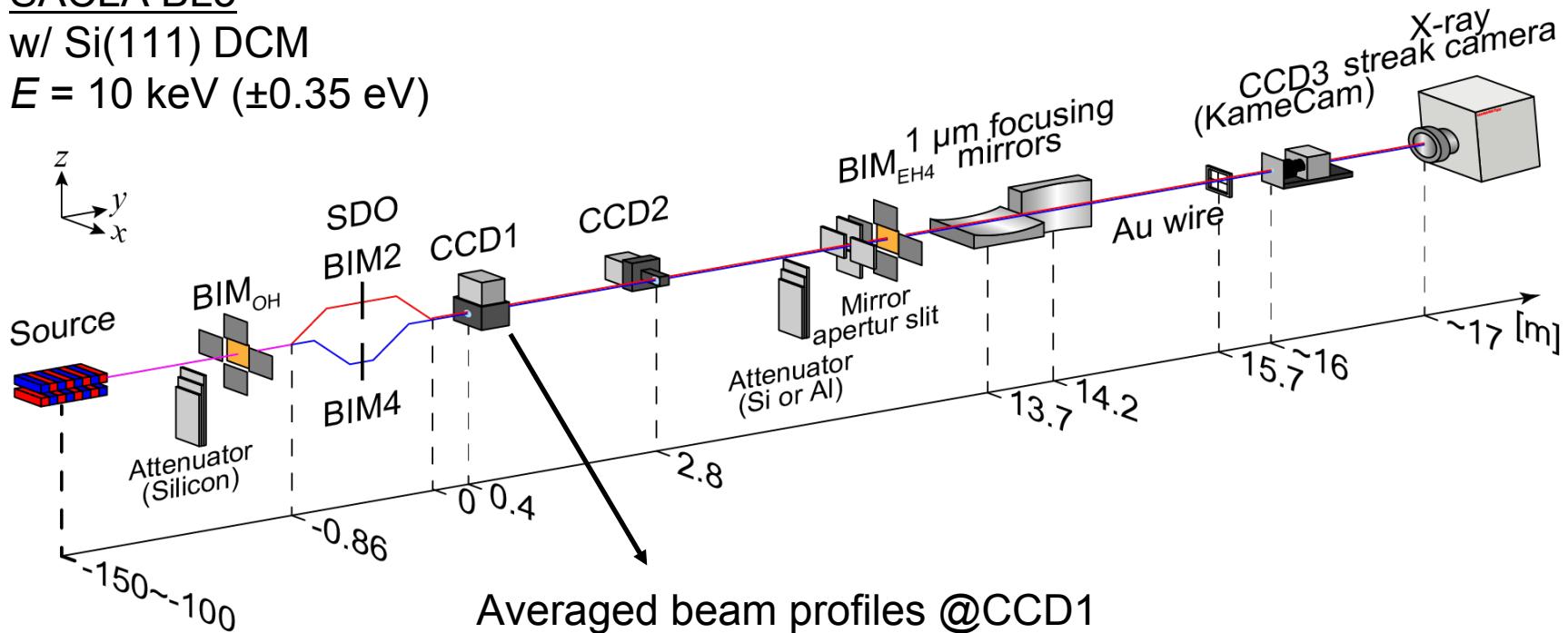
Delay time range @10 keV
-50 ~ +47 ps w/ <1 fs step
(up to 220 ps @6.5 keV)

Performance test @SACLA: Experimental setup

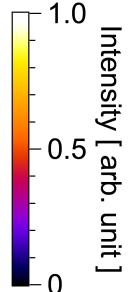
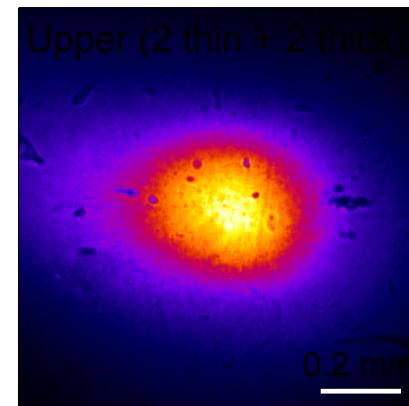
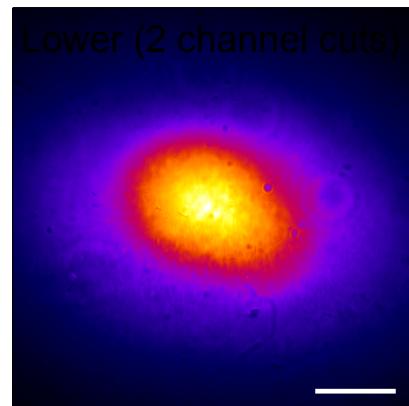
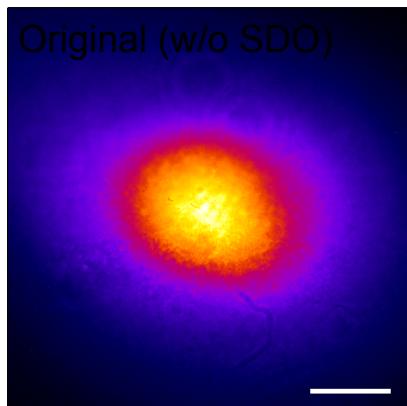
SACLA BL3

w/ Si(111) DCM

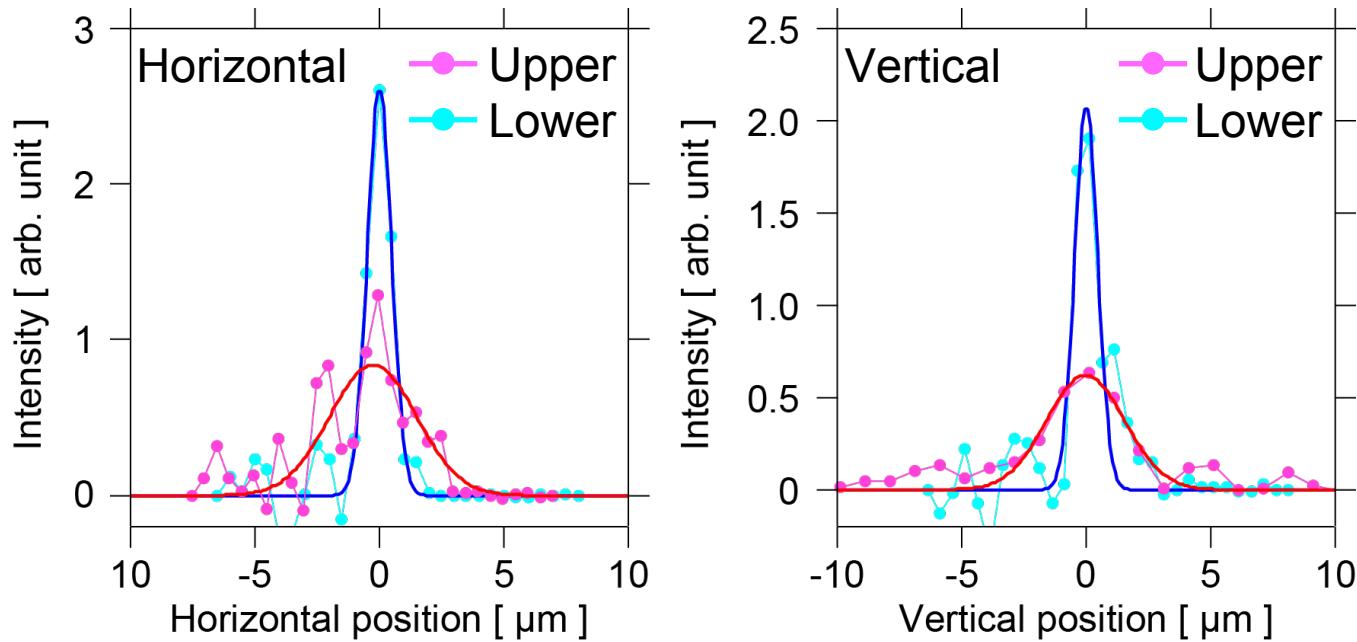
$E = 10 \text{ keV} (\pm 0.35 \text{ eV})$



Averaged beam profiles @CCD1



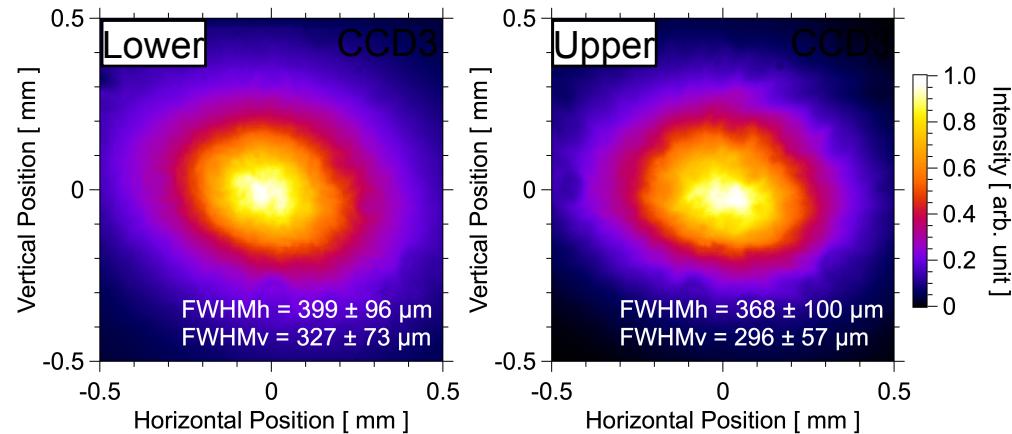
Focal profiles



Lower: $1.1 \mu\text{m} \times 1.1 \mu\text{m}$ (H \times V)

Upper: $4.1 \mu\text{m} \times 3.7 \mu\text{m}$ (H \times V)

Distortion of upper branch
mainly due to small lattice
strain in thin crystals



Beam profiles @CCD3 (16 m downstream)

Summary

- We continue to develop challenging x-ray optics
- Identification of key targets are very important;
What come next ?
e.g., Tight focusing of non-collinear two beams to single point for NL X-ray optics

End